



Condition Monitoring and Their Applications in Industry

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Message from the Guest Editors

Dear Colleagues,

Critical assets such as machinery and structures are essential for economic activities across most sectors. Condition monitoring of these critical assets is essential for optimal usage. Such monitoring processes involve detecting faults at an early stage, diagnosing the fault source and monitoring and predicting the fault progression. Achieving these objectives successfully for both machinery and structures requires use of a range of data analysis techniques that are typically developed for the specific application. While numerous theoretical data analysis, machine learning and signal processing techniques have evolved, this Special Edition presents only industrial-application-based papers in which the latest condition monitoring techniques are applied to machinery and structures.

Keywords:

- Condition monitoring
- Machinery
- Structures
- Diagnosis
- Prognosis





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Message from the Editor-in-Chief

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